	3	ea	rcn	NOT	es	
I						
l						
l						

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/658,981	SHIDLA ET AL.	
Examiner	Art Unit	
Brian J. Assessor	2114	

	SEARCHED			
Class	Subclass	Date	Examiner	
714	30	11/1/2006	ВА	
714	37	11/1/2006	ВА	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	-			
	1			

SEARCH I (INCLUDING SEAR		·)
	DATE	EXMR
EAST - ALL DATABASES	11/1/2006	ВА
INVENTOR SEARCH	11/1/2006	ВА
GOOGLE.	11/1/2006	ВА
`ACM	11/1/2006	ВА
IEEE	11/1/2006	ВА